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INFORMATION DISCLOSURE CITATION BY APPLICANT *(USE SEVERAL SHEETS IF NECESSARY)*		APPLICANT: Kenji Shimazaki et al.	
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Examiner Initial		Document No.	Date	Name	Class	Subclass	Filing Date If Appropriate
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Examiner: Mary Catherine Boler Date Considered 7/24/02

*Examiner: Initial if reference considered, regardless of whether citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.